

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-03
CB Certificate No.: 20003649 ITL

Schedule Number: IECQ-L ULTW 16.0003-03-S Rev No.: 7 Revision Date: 2024/08/07 Page 1 of 2

Appendix-1 (20003649 ITL) Schedule of Scope to Certificate of Approval

Tests	Standards/Procedures
Transmission Electron Microscope - Electron Energy Loss Spectroscopy (TEM-EELS)	T-TEM-3
Energy Dispersive Spectrometry of X-ray (EDS)	T-SEM-3, T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
Emission Microscopy (EMMI)	T-EFA-3
Emission Microscopy (EMMI)-InGaAs	T-EFA-3
Optical Beam Induced Resistance Change (OBIRCH)	T-EFA-3
Optical Microscope (OM)	T-OMI-3
3D Optical Microscope (3D OM)	T-LAB-3
IC Layout Imaging	T-OMI-3
Circuitry analysis	T-OMI-3
Thermal Emission Microscope (THEMOS)	T-EFA-3
Latch-up test	JESD78
Human Body Mode (HBM)	ANSI/ESDA/JEDEC JS-001, ANSI/ESD STM 5.1, JESD22-A114, MIL-STD-883, AEC-Q100-002
Machine Mode (MM)	ANSI/ESD S5.2, JESD22-A115, AEC-Q100-003

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Charge Device Mode (CDM)	ANSI/ESD SP5.3.2, ANSI/ESD S5.3.1, JESD22-C101, ANSI/ESDA/JEDEC JS-002, AEC-Q100-011,
Electrostatic discharge immunity test	IEC 61000-4-2
Electrical Overstress (EOS)	IEC 61000-4-5
Transmission Line Pulse (TLP)	ANSI/ESD STM5.5.1, ANSI/ESD SP5.5.2
Wire Bonding	T-EFA-3
IC Package	T-EFA-3
Pull and shear test	MIL-STD-883 method 2011.9 MIL-STD-883 method 2023.7 AEC-Q100-001, EIA/JESD22-B116, JESD22-B117
Electro-migration test	IPC TM650 2.6.25
Conductive resistance test	IPC 9701

Technical Reviewer of DQS: Paul Coug Date: 8/7/2024

